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CUSTOMER NO.: 27623 Docket Number (Optional) FORM PTO-1449 10/520,729 0002031USU/2280 Applicant INFORMATION DISCLOSURE CITATION IN AN APPLICATION Saloma et al. Group Art Unit Filing Date 2829 (Use several sheets if necessary) January 5, 2005 NOT YET ASSIGNED U. S. PATENT DOCUMENTS FILING DATE IF **EXAMINER** SUBCLASS **APPROPRIATE** CLASS DOCUMENT DATE NAME INITIAL NUMBER 356 72 Dixon et al. M_{Λ} 1/10/95 5381224 FOREIGN PATENT DOCUMENTS Translation YES NO **SUBCLASS** COUNTRY CLASS DOCUMENT DATE NUMBER XXX GERMANY (w/ Abstract) 2/4/99 19733194 κM XXX. JAPAN (w/ Abstract) 2000088929 3/31/00 OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.) Notication of Transmittal of the International Search Report or The Declaration dated 26 March MI 2003 from PCT/PH02/00013 Montangero et al. "A Som Approach to The Failure Physics of Optoelectronic Devices", Proceedings of the International Reliability Physics Symposium. Atlanta, March 23-25, 1993. New York, IEEE, US, Vol. SYMP. 31, March 23, 1993. Pp 380-385. DATE CONSIDERED EXAMINER 02/02/07 EXAMINER: Initial if citation considered, whether of not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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CUSTOMER NO.: 27623 Application Number Docket Number (Optional) **FORM PTO-1449** 10/520,729 0002031USU/2280 Applicant INFORMATION DISCLOSURE CITATION IN AN APPLICATION Saloma et al. Filing Date Group Art Unit NOT YET ASSIGNED January 5, 2005 (Use several sheets if necessary) U. S. PATENT DOCUMENTS FILING DATE IF **EXAMINER APPROPRIATE** CLASS **SUBCLASS** DOCUMENT DATE NAME INITIAL NUMBER FOREIGN PATENT DOCUMENTS Translation **CLASS SUBCLASS** YES NO COUNTRY DOCUMENT DATE NUMBER OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.) Xu et al. "Comparision of one- and two-photon optical beam-induced current imaging". Journal of Applied Physics. Vol. 86 No. 4, August 15, 1999. pp 2226-2231. DATE CONSIDERED **EXAMINER**

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